Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	2844	x adj ray near emission	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/09/15 09:07
L2	1344	L1 and detector	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/09/15 09:04
L3	536	x adj ray near emission same detector	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/09/15 09:07
L4	127	3 and substrate	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/09/15 09:08
L5	65	4 and semiconductor	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/09/15 09:09
S1	276752	x adj ray	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/09/14 09:02
S2	26374	S1 and classif$	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/09/14 09:03
S3	18084	S2 and detect$	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/09/14 09:03
S4	7690	S3 and intensity	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/09/14 09:04
S5	2861	S4 and beam	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/09/14 09:04
S6	1067	S5 and excit$5	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/09/14 09:05
S7	375	S6 and defect	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/09/14 09:05

S8	169	S7 and algorithm	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/09/14 09:07
S9	160	S8 and spectr$	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/09/14 09:07
S10	2841	x adj ray near emission	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/09/15 09:04
S11	263	S10 and defect	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/09/14 10:19
S12	177	S11 and x adj ray adj emission	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/09/14 10:20
S13	90	S12 and spectr$	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/09/14 10:20
S14	2	"6104835".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/09/14 10:20
S15	49	S13 and substrate	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/09/14 10:21
S16	33	S15 and semiconductor	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/09/14 10:21
S17	24	S16 and electron adj beam	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/09/14 10:28
S18	24	S17 and x adj ray	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2005/09/14 10:52